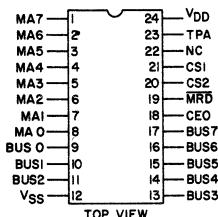


**CDP1831, CDP1831C****Product Preview**

NC = NO CONNECTION  
92CS-27584R2

**Terminal Assignment****512-Word x 8-Bit Static Read-Only Memory****Features:**

- Compatible with CDP1800 and CD4000-series devices
- On-chip address latch
- Interfaces with CDP1802 microprocessor without additional components
- Optional programmable location within 64K memory space
- Three-state outputs

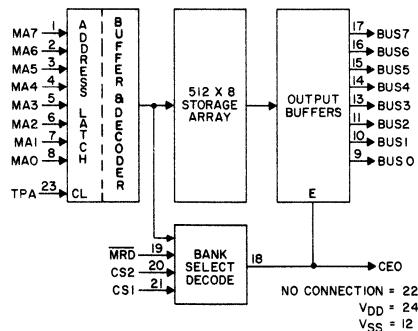
The RCA-CDP 1831 and CDP1831C types are 4096-bit mask-programmable CMOS read-only memories organized as 512 words x 8 bits and are completely static; no clocks required. They will directly interface with CDP1800-series micro-processors without additional components.

The CDP1831 and CDP1831C respond to 16-bit address multiplexed on 8 address lines. Address latches are provided on-chip to store the 8 most significant bits of the 16-bit address. By mask option, this ROM can be programmed to operate in any 512-word block within 64K memory space. The polarity of the high address strobe (TPA), and CS1 and CS2 are user mask-program-

The Chip-Enable output signal (CEO) goes "high" when the device is selected, and is intended for use as an output disable control for RAM memory in a microprocessor system.

The CDP 1831C is functionally identical to the CDP1831. The CDP1831 has an operating voltage range of 4 to 10.5 volts, and the CDP1831C has an operating voltage range of 4 to 6.5 volts.

The CDP1831 and CDP1831C types are supplied in 24-lead hermetic dual-in-line, side-brazed ceramic packages (D suffix) and in 24-lead dual-in-line plastic packages (E suffix). The CDP1831C is also available in chip form (H suffix).



92CS-27587R3

File Number 1104

**CDP1831, CDP1831C****MAXIMUM RATINGS, Absolute-Maximum Values:**DC SUPPLY-VOLTAGE RANGE, ( $V_{DD}$ )(All voltage values referenced to  $V_{SS}$  terminal)

CDP1831 ..... -0.5 to +11 V

CDP1831C ..... -0.5 to +7 V

INPUT VOLTAGE RANGE, ALL INPUTS ..... -0.5 to  $V_{DD}$  +0.5 V

DC INPUT CURRENT, ANY ONE INPUT ..... ±10 mA

POWER DISSIPATION PER PACKAGE ( $P_o$ ):For  $T_A = -40$  to  $+60^\circ\text{C}$  (PACKAGE TYPE E) ..... 500 mWFor  $T_A = +60$  to  $+85^\circ\text{C}$  (PACKAGE TYPE E) ..... Derate Linearly at 12 mW/ $^\circ\text{C}$  to 200 mWFor  $T_A = -55$  to  $+100^\circ\text{C}$  (PACKAGE TYPE D) ..... 500 mWFor  $T_A = +100$  to  $+125^\circ\text{C}$  (PACKAGE TYPE D) ..... Derate Linearly at 12 mW/ $^\circ\text{C}$  to 200 mW

## DEVICE DISSIPATION PER OUTPUT TRANSISTOR

FOR  $T_A = \text{FULL PACKAGE-TEMPERATURE RANGE}$  ..... 100 mWOPERATING-TEMPERATURE RANGE ( $T_A$ )PACKAGE TYPE D ..... -55 to  $+125^\circ\text{C}$ PACKAGE TYPE E ..... -40 to  $+85^\circ\text{C}$ STORAGE TEMPERATURE RANGE ( $T_{STG}$ ) ..... -65 to  $+150^\circ\text{C}$ 

## LEAD TEMPERATURE (DURING SOLDERING)

At distance  $1/16 \pm 1/32$  inch ( $1.59 \pm 0.79$  mm) from case for 10 s max .....  $+265^\circ\text{C}$ **OPERATING CONDITIONS** at  $T_A = \text{Full Package-Temperature Range}$ . For maximum reliability, operating conditions should be selected so that operation is always within the following ranges:

| CHARACTERISTIC             | LIMITS   |          |          |          | UNITS |  |
|----------------------------|----------|----------|----------|----------|-------|--|
|                            | CDP1831  |          | CDP1831C |          |       |  |
|                            | Min.     | Max.     | Min.     | Max.     |       |  |
| DC Operating Voltage Range | 4        | 10.5     | 4        | 6.5      | V     |  |
| Input Voltage Range        | $V_{SS}$ | $V_{DD}$ | $V_{SS}$ | $V_{DD}$ |       |  |

**STATIC ELECTRICAL CHARACTERISTICS** at  $T_A = -40$  to  $+85^\circ\text{C}$ , Except as noted

| CHARACTERISTIC                               | CONDITIONS   |                 |                 | LIMITS  |               |          |       | UNITS         |  |
|--|--------------|-----------------|-----------------|---------|---------------|----------|-------|---------------|--|
|  | $V_o$<br>(V) | $V_{IN}$<br>(V) | $V_{DD}$<br>(V) | CDP1831 |               | CDP1831C |       |               |  |
|  |              |                 |                 | Min.    | Typ.*         | Max.     | Min.  |               |  |
| Quiescent Device Current, $I_{DD}$           | —            | 5               | 5               | —       | 0.01          | 50       | —     | $\mu\text{A}$ |  |
|  | —            | 10              | 10              | —       | 1             | 200      | —     |               |  |
| Output Low Drive (Sink) Current, $I_{OL}$    | 0.4          | 0.5             | 5               | 0.55    | —             | —        | 0.55  | —             |  |
|  | 0.5          | 0.10            | 10              | 1.30    | —             | —        | —     | —             |  |
| Output High Drive (Source) Current, $I_{OH}$ | 4.6          | 0.5             | 5               | -0.35   | —             | —        | -0.35 | —             |  |
|  | 9.5          | 0.10            | 10              | -0.65   | —             | —        | —     | —             |  |
| Output Voltage Low-Level, $V_{OL}$           | —            | 0.5             | 5               | —       | 0             | 0.1      | —     | mA            |  |
|  | —            | 0.10            | 10              | —       | 0             | 0.1      | —     |               |  |
| Output Voltage High Level, $V_{OH}$          | —            | 0.5             | 5               | 4.9     | 5             | —        | 4.9   | —             |  |
|  | —            | 0.10            | 10              | 9.9     | 10            | —        | —     | —             |  |
| Input Low Voltage, $V_{IL}$                  | 0.5, 4.5     | —               | 5               | —       | —             | 1.5      | —     | V             |  |
|  | 1.9          | —               | 10              | —       | —             | 3        | —     |               |  |
| Input High Voltage, $V_{IH}$                 | 0.5, 4.5     | —               | 5               | 3.5     | —             | —        | 3.5   | —             |  |
|  | 1.9          | —               | 10              | 7       | —             | —        | —     | —             |  |
| Input Leakage Current, $I_{IN}$              | Any          | 0.5             | 5               | —       | $\pm 10^{-4}$ | ±1       | —     | mA            |  |
|  | Input        | 0.10            | 10              | —       | $\pm 10^{-4}$ | ±2       | —     |               |  |
| 3-State Output Leakage Current, $I_{OUT}$    | 0.5          | 0.5             | 5               | —       | $\pm 10^{-4}$ | ±1       | —     | $\mu\text{A}$ |  |
|  | 0.10         | 0.10            | 10              | —       | $\pm 10^{-4}$ | ±2       | —     |               |  |
| Input Capacitance, $C_{IN}$                  | —            | —               | —               | —       | 5             | 7.5      | —     | pF            |  |
| Output Capacitance, $C_{OUT}$                | —            | —               | —               | —       | 10            | 15       | —     |               |  |
| Operating Current, $I_{DD1\dagger}$          | —            | 0.5             | 5               | —       | 5             | 10       | —     | mA            |  |
|  | —            | 0.10            | 10              | —       | 10            | 20       | —     |               |  |

\*Typical values are for "one"  $T_A = 25^\circ\text{C}$   
and nominal  $V_{DD}$ †Outputs open-circuited, cycle time = 2.5  $\mu\text{s}$

**CDP1831, CDP1831C**

**DYNAMIC ELECTRICAL CHARACTERISTICS** at  $T_A = -40$  to  $+85^\circ\text{C}$ ,  $V_{DD} \pm 5\%$ ,  
Input  $t_r, t_f = 10$  ns,  $C_L = 50$  pF,  $R_L = 200\text{k}\Omega$

| CHARACTERISTIC                                  | TEST CONDITIONS<br>$V_{DD}$<br>(V) | LIMITS  |       |      |          |       |      | UNITS |  |
|---|------------------------------------|---------|-------|------|----------|-------|------|-------|--|
|   |                                    | CDP1831 |       |      | CDP1831C |       |      |       |  |
|   |                                    | Min.+   | Typ.* | Max. | Min.+    | Typ.* | Max. |       |  |
| Access Time from Address Change, $t_{AA}$       | 5                                  | —       | 850   | 1000 | —        | 850   | 1000 | ns    |  |
|   | 10                                 | —       | 350   | 400  | —        | —     | —    |       |  |
| Access Time from Chip Select, $t_{ACS}$         | 5                                  | —       | 700   | 800  | —        | 700   | 800  |       |  |
|   | 10                                 | —       | 250   | 300  | —        | —     | —    |       |  |
| Chip Select Delay, $t_{CS}$                     | 5                                  | —       | 600   | —    | —        | 600   | —    |       |  |
|   | 10                                 | —       | 200   | 300  | —        | —     | —    |       |  |
| Address Setup Time, $t_{AS}$                    | 5                                  | 50      | —     | —    | 50       | —     | —    |       |  |
|   | 10                                 | 25      | —     | —    | —        | —     | —    |       |  |
| Address Hold Time, $t_{AH}$                     | 5                                  | 150     | —     | —    | 150      | —     | —    |       |  |
|   | 10                                 | 75      | —     | —    | —        | —     | —    |       |  |
| Read Delay, $t_{MRD}$                           | 5                                  | —       | 300   | 500  | —        | 300   | 500  |       |  |
|   | 10                                 | —       | 100   | 150  | —        | —     | —    |       |  |
| Chip Enable Output Delay from Address, $t_{CA}$ | 5                                  | —       | 500   | 600  | —        | 500   | 600  |       |  |
|   | 10                                 | —       | 200   | 250  | —        | —     | —    |       |  |
| Bus Contention Delay, $t_b$                     | 5                                  | —       | 200   | 350  | —        | 200   | 350  |       |  |
|   | 10                                 | —       | 100   | 150  | —        | —     | —    |       |  |
| TPA Pulse Width, $t_{PAW}$                      | 5                                  | 200     | —     | —    | 200      | —     | —    |       |  |
|   | 10                                 | 70      | —     | —    | —        | —     | —    |       |  |

†Time required by a limit device to allow for the indicated function.

\*Time required by a typical device to allow for the indicated function. Typical values are for  $T_A = 25^\circ\text{C}$  and nominal  $V_{DD}$ .

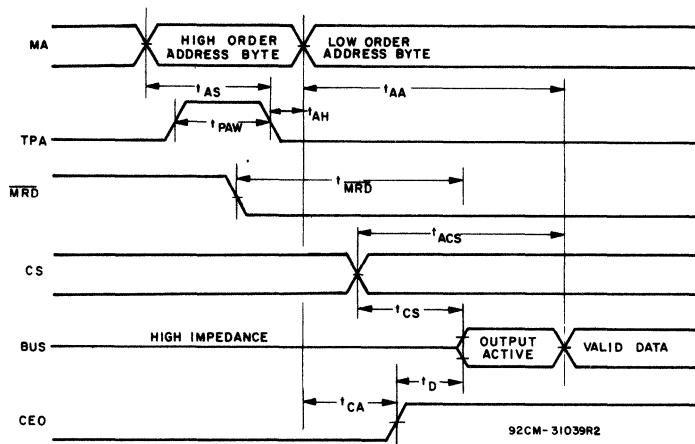


Fig. 2 - Timing waveforms.

**CDP1831, CDP1831C****Note:**

The dynamic characteristics and timing diagrams indicate maximum performance capability of the CDP1831. When used directly with a CDP1800-series microprocessor, timing will be determined by the clock frequency and internal delays of the microprocessor.

The following general timing relationships will hold when the CDP1831 is used with a CDP1800-series microprocessor:

$$t_{AH} = 0.5 t_c$$

$$t_{PAW} = 1 t_c$$

MRD occurs one clock period ( $t_c$ ) earlier than the address bits MA0-MA7.

$$\text{where } t_c = \frac{1}{\text{CPU clock frequency}}$$